

Test Cost Trends and Opportunities



Marc Mydill
TI Fellow, Manager Test Technology Center
Texas Instruments Inc.

Abstract :

Despite niches of success, test is often one of the weakest links in the overall Semiconductor manufacturing flow. Cost, efficiency, cycle time, resource utilization and even quality can all be negatively impacted by test. This presentation will investigate why test is such an overall cost burden today, how it is slowly changing and how to accelerate change looking forward.

Speaker's Biography :

Marc Mydill presently manages TI's Test Technology Center, providing broad engineering support for test, test infrastructure and test strategy at TI. In his 33 years at TI, Marc has worked with factories, product groups, equipment suppliers, industry groups and customers on a broad range of test related assignments and projects including automatic test equipment (ATE) development, manufacturing test operations, test roadmaps, test infrastructure, test cost and productivity, test applications, testability strategies and quality improvement. Marc holds 10 patents related to test system architecture and test methods.

Marc has degrees from Southern Illinois University (BSEE), and Southern Methodist University (MSEE) and is a member of Tau Beta Pi national engineering honor society.